



Docket No.: OGOSH39USA

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No. : 10/549,440 Confirmation No. 5587
Applicant : Takeo Okabe
371 Filed : September 16, 2005
Art Unit : 1746
Examiner :
Customer No. : 00270
Title : COPPER ALLOY SPUTTERING TARGET, PROCESS FOR
PRODUCING THE SAME AND SEMICONDUCTOR
ELEMENT WIRING

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE UNDER 37 CFR 1.8(a)

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail on the date indicated below in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

Signature

Date

1-26-2006

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

In compliance with their duty to disclose under 37 CFR §1.56(a), Applicant and his attorneys enclose a form PTO-1449 and copies of the foreign and other documents listed therein.

The cited references were cited in the International Search Report for International Application No. PCT/IP04/01914 or are related to the background art discussed on pages 2-3 of the present application. The cited U.S. Patent Application Publications are assigned to the assignee of the present application and are being cited to the Examiner for consideration with respect to double patenting issues only.

The Examiner is respectfully requested to consider the cited documents and to make the same of record in the file of the present application.

In the event that a fee for the Information Disclosure Statement is required, please charge the fee to our Deposit Account No. 08-3040.

Respectfully submitted,
HOWSON AND HOWSON
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Sheet 1 of 1

Form PTO-1449 U.S. Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT	Atty. Docket No. OGOSH39USA	Serial No. 10/549,440
	Applicant: Takeo Okabe	
	371 (c) Date: September 16, 2005	Group Art Unit: 1746 1793

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Subclass
/S.I./	5,023,698	6/1991	Kobayashi et al.	357	67
/S.I./	2005/0121320 A1	6/2005	Okabe et al.	204	298.13
/S.I./	2005/0285273 A1	12/2005	Okabe et al.	257	762

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation	
				Yes	No
/S.I./	JP 2002-004048	1/2002	Japan	Abstract only	x
/S.I./	JP 2001-284358	10/2001	Japan	Abstract only	x
/S.I./	JP 2002-294437	10/2002	Japan	Abstract only	x
/S.I./	JP 11-158614	6/1999	Japan	Abstract only	x
/S.I./	WO 03/064722 A1	8/2003	Japan	See US 2005/0121320 A1 cited above	
/S.I./	EP 0601509 A1	6/1994	European		
/S.I./	JP 10-060633	3/1998	Japan	Abstract only	x

Other Documents (including Author, Title, Date, Pertinent Pages, Etc.)

	Patent Abstracts of Japan, 1 page English Abstract of JP 2002-004048, 1/2002
	Patent Abstracts of Japan, 1 page English Abstract of JP 2001-284358, 1/2002
	Patent Abstracts of Japan, 1 page English Abstract of JP 2002-294437, 10/2002
	Patent Abstracts of Japan, 1 page English Abstract of JP 11-158614, 6/1999
	esp@cnict database, 1 page English Abstract of JP 10-060633, 3/1998
Examiner	/Sikylin lp/
Date Considered	
07/20/2008	

Duplicates
See
translation
above

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.